

## MODA

### **Physics-based Model: Electronic – Statistical charge transport – Fermi Golden Rule hopping model (RoMM 1.6.2)**

1 ASPECT OF THE USER CASE/SYSTEM TO BE SIMULATED	
1.1	<p><b>ASPECT OF THE USER CASE TO BE SIMULATED</b></p> <p>Transport of electrons between coarse grained representations of molecules.</p>
1.2	<p><b>MATERIAL</b></p> <p><i>P3HT:PCBM, PCDTBT:PCBM, etc</i></p>
1.3	<p><b>GEOMETRY</b></p> <p><i>Up to 100x100x100 nm<sup>3</sup> domains containing the bulk heterojunction</i></p>
1.4	<p><b>TIME LAPSE</b></p> <p><i>up to ms</i></p>
1.5	<p><b>MANUFACTURING PROCESS OR IN-SERVICE CONDITIONS</b></p>
1.6	<p><b>PUBLICATION ON THIS DATA</b></p>

2 GENERIC PHYSICS OF THE MODEL EQUATION	
2.0	<p><b>MODEL TYPE AND NAME</b></p> <p>Statistical charge transport model</p>
2.1	<p><b>MODEL ENTITY</b></p> <p>Electrons</p>
2.2	<p><b>MODEL PHYSICS/CHEMISTRY EQUATION PE</b></p> <p><b>Equation</b></p> <p>Semi-classical Marcus charge transport theory in the high temperature limit.</p>
	<p><b>Physical quantities</b></p> <p>Charge, current density and field profiles.</p>
2.3	<p><b>MATERIALS RELATIONS</b></p> <p><b>Relation</b></p> <p>Charge transfer (hopping) rates based on Fermi's Golden Rule:</p> $\omega_{ij} = \frac{J_{ij}}{\hbar} \sqrt{\frac{\pi}{\lambda_{ij} k_B T}} \exp\left(-\frac{(\Delta E_{ij} - \lambda_{ij})^2}{4\lambda_{ij} k_B T}\right)$

		<b>Physical quantities/descriptors for each MR</b>	Reorganization energies ( $\lambda_{ij}$ ), site energy differences ( $\Delta E_{ij}$ ), electronic coupling elements ( $J_{ij}$ ), charge transfer rates ( $\omega_{ij}$ ).
2.4	<b>SIMULATED INPUT</b>	From CGMD: Coarse grain molecular geometry. From DFT: Reorganization energies, site energy differences, electronic couplings.	

<b>3 SOLVER AND COMPUTATIONAL TRANSLATION OF THE SPECIFICATIONS</b>			
3.1	<b>NUMERICAL SOLVER</b>	Kinetic Monte Carlo	
3.2	<b>SOFTWARE TOOL</b>	In-house KMC solver.	
3.3	<b>TIME STEP</b>		
3.4	<b>COMPUTATIONAL REPRESENTATION</b>	<b>PHYSICS EQUATION, MATERIAL RELATIONS, MATERIAL</b>	Site occupation probability $p_i$ obeys the steady state rate equation $\frac{\partial p_i}{\partial t} = -\sum_j [\omega_{ij} p_i (1 - p_j) - \omega_{ji} p_j (1 - p_i)] = 0$ . Waiting time for an event step between sites $i$ and $j$ is $\tau_{ij} = -\frac{\ln(r)}{\omega_{ij}}$ , where $r$ is a random number (0,1).
3.5	<b>COMPUTATIONAL BOUNDARY CONDITIONS</b>	Electrostatic bias across simulation cell	
3.6	<b>ADDITIONAL SOLVER PARAMETERS</b>		

<b>4 POST PROCESSING</b>		
4.1	<b>THE PROCESSED OUTPUT</b>	Current density, carrier mobility  Output (carrier mobility) will be used in larger finite volume simulations of continuum electrics (drift-diffusion).
4.2	<b>METHODOLOGIES</b>	Current density is obtained from carrier flux, charge mobility from drift velocity of carriers in an external field.
4.3	<b>MARGIN OF ERROR</b>	